SUPERSEDES: NONE

4395A Network/Spectrum/Impedance Analyzer

Serial Numbers: JP1KE00101 / JP1KE01993

Sprious on the trace trouble in Network measurement mode

To Be Performed By: Agilent-Qualified Personnel

Parts Required:

P/N	Description	Quanty
E4970-69505	A5 Synthesizer Board	1

Situation:

The above serial numbered 4395A may have sprious trouble on it's trace in Network measurement mode due to the design problem in synthesizer board.

Continued

DATE: July 2001

ADMINISTRATIVE INFORMATION

SERVICE NOTE CLASSIFICATION:				
MODIFICATION RECOMMENDED				
ACTION CATEGORY:	☐ IMMEDIATELY ■ ON SPECIFIED FAILURE ☐ AGREEABLE TIME	STANDARDS: LABOR 5.0 Hours		
LOCATION CATEGORY:	☐ CUSTOMER INSTALLABLE ☐ ON-SITE ■ SERVICE CENTER	SERVICE INVENTORY: ☐ RETURN ☐ SCRAP ☐ SEE TEXT	USED PARTS: ■ RETURN ☐ SCRAP ☐ SEE TEXT	
AVAILABILITY:	PRODUCT'S SUPPORT LIFE	AGILENT RESPONSIBLE UNTIL:		
AUTHOR: HYM	ENTITY: 3355	ADDITIONAL INFORMATION: July 2003		

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Solution / Action:

Perform a test as following procedure

1. Connect a Type-N cable between RF-OUT and B input (can be R or A)

2. Meas -- Analyzer type -- : NA

3. Meas : A/R

4. Format : phase

5. IF BW : 1 KHz

6. Set following center and span frequency. Center : 350 MHz Span : 300 MHz Number of Points: About 450

If there is unexpected noise on the trace, replace the A5 Synthesizer board with new one (P/N:E4970-69505), then perform adjustments and verification test as follows.

Adjustment required after replacing A5 assembly

Local DAC Adjustment

- Source Power Adjustment
- Source Flatness Adjustment
- Input Local Null Adjustment
- Receiver Gain Adjustment
- IF 8 dB/16 dB Gain Adjustment
- Temperature Adjustment
- Receiver Gain Adjustment
- Receiver Attenuator Adjustment
- IF BPF Flatness Adjustment
- Performance test Frequency Accuracy Test
- Source Level/Flatness Test
- Non-sweep Linearity Test
- Power Sweep Linearity Test
- Harmonics/Non-harmonic Test
- Receiver Noise Level Test

- Input Crosstalk Test
- Absolute Amplitude Accuracy Test
- Magnitude Ratio/Phase Dynamic Accuracy Test
- Magnitude Ratio/Phase Frequency Accuracy Test
- Display Average Noise Level Test
- Amplitude Fidelity Test
- Input Attenuator Switching Uncertainty Test
- Noise Sidebands Test
- Amplitude Accuracy/Frequency Response Test
- Second Order Intermodulation Distortion Test
- Other Spurious Test
- Residual Response Test